

<b>Notice of References Cited</b>	Application/Control No. 10/666,316		Applicant(s)/Patent Under Reexamination DEFAIX ET AL.	
	Examiner Phillip H. Nguyen		Art Unit 2191	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,681,225	01-2004	Uceda-Sosa et al.	707/8
*	B	US-5,623,659	04-1997	Shi et al.	707/8
*	C	US-7,281,050	10-2007	Dinker et al.	709/229
*	D	US-6,393,437	05-2002	Zinda et al.	707/201
*	E	US-6,393,437	05-2002	Zinda et al.	707/201
*	F	US-6,757,893	06-2004	Haikin, John S.	717/170
*	G	US-6,185,563	02-2001	Hino, Yosuke	707/8
*	H	US-6,026,474	02-2000	Carter et al.	711/202
*	I	US-5,935,207	08-1999	Logue et al.	709/219
*	J	US-6,035,281	03-2000	Crosskey et al.	705/14
*	K	US-6,286,006	09-2001	Bharat et al.	707/100
*	L	US-6,513,061	01-2003	Ebata et al.	709/203
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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